REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Drawing updated to reflect current requirements. -ro	02-01-11	R. MONNIN
B	Five year review requirement. -rrp	09-11-10	C. SAFFLE

REV																				
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REV STATUS	REV	B	B	B	B	B	B	B	B	B	B	B	B	B	B
OF SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	

PMIC N/A

PREPARED BY
RICK C. OFFICER

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COLUMBUS, OHIO 43218-3990
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STANDARD MICROCIRCUIT DRAWING

THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE

AMSC N/A

CHECKED BY
RAJESH R. PITHADIA

APPROVED BY
MICHAEL A. FRYE

DRAWING APPROVAL DATE
94-03-01

MICROCIRCUIT, LINEAR, LOW NOISE WIDEBAND VARIABLE GAIN AMPLIFIER, MONOLITHIC SILICON

REVISION LEVEL	SIZE	CAGE CODE	
B	A	**67268**	**5962-94572**

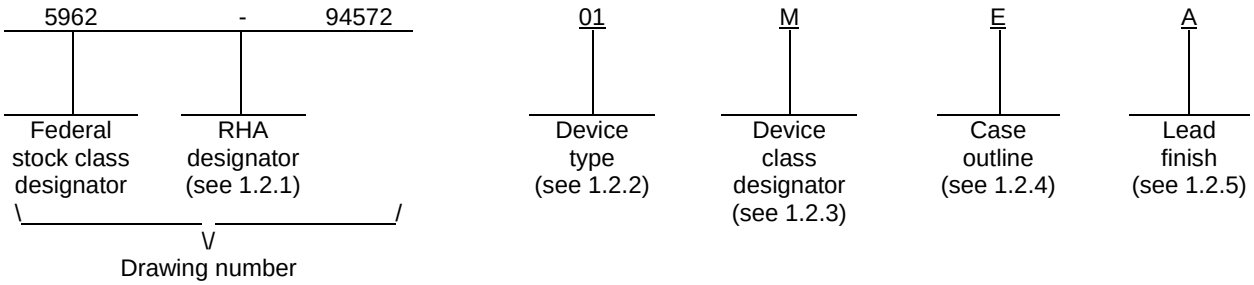
SHEET 1 OF 13

DSCC FORM 2233
APR 97

1. SCOPE

1.1 Scope. This drawing documents two product assurance class levels consisting of high reliability (device classes Q and M) and space application (device class V). A choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of Radiation Hardness Assurance (RHA) levels is reflected in the PIN.

1.2 PIN. The PIN is as shown in the following example:



1.2.1 RHA designator. Device classes Q and V RHA marked devices meet the MIL-PRF-38535 specified RHA levels and are marked with the appropriate RHA designator. Device class M RHA marked devices meet the MIL-PRF-38535, appendix A specified RHA levels and are marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) identify the circuit function as follows:

Device type	Generic number	Circuit function
01	AD600	Dual, low noise, 35 MHz variable gain amplifier
02	AD602	Dual, low noise, 35 MHz variable gain amplifier
03	AD603	Single, low noise, 90 MHz variable gain amplifier

1.2.3 Device class designator. The device class designator is a single letter identifying the product assurance level as follows:

Device class	Device requirements documentation
M	Vendor self-certification to the requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A
Q or V	Certification and qualification to MIL-PRF-38535

1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	Terminals	Package style
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line
P	GDIP1-T8 or CDIP2-T8	8	Dual-in-line

1.2.5 Lead finish. The lead finish is as specified in MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

1.3 Absolute maximum ratings. 1/

Total supply voltage ($\pm V_S$)	±7.5 V
Input voltages:	
C1LO, C2LO, C2HI, and C1HI pins	$\pm V_S$
A1HI, A1LO, A2LO, and A2HI pins	±2 V continuous; $\pm V_S$ for 10 ms
GAT1 and GAT2 pins	$\pm V_S$
Internal power dissipation (P_D):	
Case E	600 mW
Case P	400 mW
Transistor count:	
Device types 01 and 02	415 BJT
Device type 03	100 BJT
Storage temperature range	-65°C to +150°C
Lead temperature range (soldering 60 seconds)	+300°C
Thermal resistance, junction-to-case (θ_{JC})	See MIL-STD-1835
Thermal resistance, junction-to-ambient (θ_{JA}):	
Case E	120°C/W
Case P	140°C/W

1.4 Recommended operating conditions.

Ambient operating temperature range (T_A)	-55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at http://assist.daps.dla.mil/quicksearch/ or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device classes Q and V shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. The individual item requirements for device class M shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein for device classes Q and V or MIL-PRF-38535, appendix A and herein for device class M.

3.2.1 Case outline. The case outline shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device. For RHA product using this option, the RHA designator shall still be marked. Marking for device classes Q and V shall be in accordance with MIL-PRF-38535. Marking for device class M shall be in accordance with MIL-PRF-38535, appendix A.

3.5.1 Certification/compliance mark. The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-PRF-38535. The compliance mark for device class M shall be a "C" as required in MIL-PRF-38535, appendix A.

3.6 Certificate of compliance. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.6.1 herein). For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6.2 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and herein or for device class M, the requirements of MIL-PRF-38535, appendix A and herein.

3.7 Certificate of conformance. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 or for device class M in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DSCC-VA of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change that affects this drawing.

3.9 Verification and review for device class M. For device class M, DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 Microcircuit group assignment for device class M. Device class M devices covered by this drawing shall be in microcircuit group number 49 (see MIL-PRF-38535, appendix A).

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions $-55°C \le T_A \le +125°C$ $V_S = \pm 5.0$ V unless otherwise specified	Group A subgroups	Device type	Limits 1/		Unit
					Min	Max	
Minimum input resistance	R_{IN}	A1HI to A1LO pins and A2LO to A2HI pins	1,2,3	01	95		Ω
				02	95		
		V_{IN} to COMM pins		03	97		
Maximum input resistance	R_{IN}	A1HI to A1LO pins and A2LO to A2HI pins	1,2,3	01		105	Ω
				02		105	
		V_{IN} to COMM pins		03		103	
Peak output 2/ 3/	V_{OS} min	$R_L \ge 500\ \Omega$, $C_L = 5$ pF	1,2,3	01,02	±2.5		V
				03	±2.3		
Gain error	GE1 min	0 dB to +3 dB gain	1,2,3	01		-1.5	dB
		-10 dB to -7 dB gain		02		-1.5	
	GE1 max	0 dB to +3 dB gain		01		+2.5	
		-10 dB to –7 dB gain		02		+2.5	
	GE2 min	+3 dB to +37 dB gain		01		-1.5	
		-7 dB to +27 dB gain		02		-1.5	
	GE2 max	+3 dB to +37 dB gain		01		+1.5	
		-7 dB to +27 dB gain		02		+1.5	

See footnotes at end of table.

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions $-55°C \le T_A \le +125°C$ $V_S = \pm 5.0$ V unless otherwise specified	Group A subgroups	Device type	Limits 1/		Unit
					Min	Max	
Gain error	GE3 min	+37 dB to +40 dB gain	1,2,3	01		-2.5	dB
		+27 dB to +30 dB gain		02		-2.5	
	GE3 max	+37 dB to +40 dB gain		01		+1.5	
		+27 dB to +30 dB gain		02		+1.5	
	GE min	V_G = -500 mV to +500 mV		03		-2.0	
	GE max					+2.0	
Output offset voltage 4/	V_{OSO1}	V_G = -625 mV to +625 mV	1,2,3	01		75	mV
				02		55	
		V_G = -500 mV to +500 mV		03		30	
Output offset voltage gain off	V_{OSO2}		1,2,3	01,02		±500	mV
Output offset variation	V_{OSV}	V_G = -625 mV to +625 mV	1,2,3	01		75	mV
				02		55	
		V_G = -500 mV to +500 mV		03		30	
Gain scaling factor	SF min	+3 dB to +37 dB gain	1,2,3	01		29	dB/V
		-7 dB to +27 dB gain		02		29	
		-500 mV to +500 mV		03		37	
Gain scaling factor	SF max	+3 dB to +37 dB gain	1,2,3	01		35	dB/V
		-7 dB to +27 dB gain		02		35	
		-500 mV to +500 mV		03		43	

See footnotes at end of table.

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions $-55°C \le T_A \le +125°C$ $V_S = \pm 5.0$ V unless otherwise specified	Group A subgroups	Device type	Limits 1/		Unit
					Min	Max	
Logic input "LOW" (output ON)	V_{IL}	2/	1,2,3	01,02		0.8	V
Logic input "HIGH" (output ON)	V_{IH}	2/	1,2,3	01,02	2.4		V
Specified operating voltage	V_S max	2/	1,2,3	All		5.25	V
	V_S min				-4.75		
Quiescent current	I_Q		1,2,3	01,02		30	mA
				03		20	

1/ The limiting terms "min" (minimum) and "max" (maximum) shall be considered to apply to magnitudes only. Negative current shall be defined as conventional current flow out of a device terminal.

2/ If not tested, shall be guaranteed to the limits specified in table I herein.

3/ Use resistive loads of 500 Ω or greater, or with the addition of a 1 kΩ pull-down resistor when driving lower loads.

4/ The dc gain of the main amplifier in device type 01 is 113 times; thus an input offset of only 100 μV becomes an 11.3 mV output offset. In device types 02 and 03, amplifier's gain is 35.7 times; thus, an input offset of 100 μV becomes a 3.57 mV output offset.

Device types	01 and 02	03
Case outlines	E	P
Terminal number	Terminal symbol	
1	C1LO	GPOS
2	A1HI	GNEG
3	A1LO	V_{IN}
4	GAT1	COMM
5	GAT2	FDBK
6	A2LO	VNEG
7	A2HI	VOUT
8	C2LO	VPOS
9	C2HI	---
10	A2CM	---
11	A2OP	---
12	VNEG	---
13	VPOS	---
14	A1OP	---
15	A1CM	---
16	C1HI	---

FIGURE 1. Terminal connections.

Device types	01 and 02
Terminal symbol	Description
C1LO	Channel 1 gain control input “LOW”. Positive voltage reduces CH1 gain.
A1HI	Channel 1 signal input “HIGH”. Positive voltage increases CH1 output.
A1LO	Channel 1 signal input “LOW”. Usually taken to CH1 input ground.
GAT1	Channel 1 gating input. A logic “HIGH” shuts off channel 1 signal path.
GAT2	Channel 2 gating input. A logic “HIGH” shuts off channel 2 signal path.
A2LO	Channel 2 signal input “LOW”. Usually taken to channel 2 input ground.
A2HI	Channel 2 signal input “HIGH”. Positive voltage increases channel 2 output.
C2LO	Channel 2 gain control input “LOW”. Positive voltage reduces channel 2 gain.
C2HI	Channel 2 gain controlled input “HIGH”. Positive voltage increases channel 2 gain.
A2CM	Channel 2 common. Usually taken to channel 2 output ground.
A2OP	Channel 2 output.
VNEG	Negative supply for both amplifiers.
VPOS	Positive supply for both amplifiers.
A1OP	Channel 1 output.
A1CM	Channel 1 common. Usually taken to channel 1 output ground.
C1HI	Channel 1 gain control input “HIGH”. Positive voltage increases channel 1 gain.

FIGURE 1. Terminal connections – Continued.

Device type	03
Terminal symbol	Description
GPOS	Gain control input “HIGH”. Positive voltage increases gain.
GNEG	Gain control input “LOW”. Negative voltage increases gain.
V_{IN}	Amplifier input.
COMM	Amplifier ground.
FDBK	Connection to feedback network.
VNEG	Negative supply input.
VOUT	Amplifier output.
VPOS	Positive supply input.

FIGURE 1. Terminal connections – Continued.

4. VERIFICATION

4.1 Sampling and inspection. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. For device class M, sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection.

4.2.1 Additional criteria for device class M.

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition B. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.

(2) T_A = +125°C, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein.

4.2.2 Additional criteria for device classes Q and V.

a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.

b. Interim and final electrical test parameters shall be as specified in table II herein.

c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in MIL-PRF-38535, appendix B.

4.3 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-PRF-38535. Inspections to be performed shall be those specified in MIL-PRF-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4 Conformance inspection. Technology conformance inspection for classes Q and V shall be in accordance with MIL-PRF-38535 including groups A, B, C, D, and E inspections and as specified herein. Quality conformance inspection for device class M shall be in accordance with MIL-PRF-38535, appendix A and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 4, 5, 6, 7, 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

TABLE II. Electrical test requirements.

Test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)	Subgroups (in accordance with MIL-PRF-38535, table III)	
	Device class M	Device class Q	Device class V
Interim electrical parameters (see 4.2)	1	1	1
Final electrical parameters (see 4.2)	1, 2, 3 1/	1, 2, 3 1/	1, 2, 3 1/
Group A test requirements (see 4.4)	1, 2, 3	1, 2, 3	1, 2, 3
Group C end-point electrical parameters (see 4.4)	1	1	1, 2, 3
Group D end-point electrical parameters (see 4.4)	1	1	1, 2, 3
Group E end-point electrical parameters (see 4.4)	---	---	---

1/ PDA applies to subgroup 1.

4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table II herein.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

a. Test condition B. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.

b. T_A = +125°C, minimum.

c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table II herein.

4.4.4 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein).

a. End-point electrical parameters shall be as specified in table II herein.

b. For device classes Q and V, the devices or test vehicle shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535 for the RHA level being tested. For device class M, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535, appendix A for the RHA level being tested. All device classes must meet the post irradiation end-point electrical parameter limits as defined in table I at T_A = +25°C ±5°C, after exposure, to the subgroups specified in table II herein.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor prepared specification or drawing.

6.1.2 Substitutability. Device class Q devices will replace device class M devices.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.3 Record of users. Military and industrial users should inform Defense Supply Center Columbus (DSCC) when a system application requires configuration control and which SMD's are applicable to that system. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.4 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0547.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535 and MIL-HDBK-1331.

6.6 Sources of supply.

6.6.1 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DSCC-VA and have agreed to this drawing.

6.6.2 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 09-11-10

Approved sources of supply for SMD 5962-94572 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DSCC maintains an online database of all current sources of supply at http://www.dscc.dla.mil/Programs/Smcr/.

Standard microcircuit drawing PIN 1/	Vendor CAGE number	Vendor similar PIN 2/
5962-9457201MEA	24355	AD600SQ/883B
5962-9457202MEA	24355	AD602SQ/883B
5962-9457203MPA	24355	AD603SQ/883B

1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.

2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
24355	Analog Devices Route 1 Industrial Park P.O. Box 9106 Norwood, MA 02062 Point of contact: 804 Woburn Street Wilmington, MA 01887-3462

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.

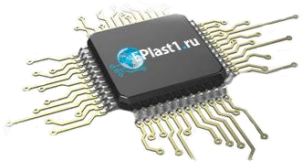
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- Консультации по применению компонента;
- Поставка образцов и прототипов;
- Техническая поддержка проекта;
- Защита от снятия компонента с производства.



Как с нами связаться

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